Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
09/967,084	BEIER ET AL.
Examiner	Art Unit
Michael Y. Won	2155

SEARCHED				
Class	Subclass	Date	Examiner	
709	212, 214, 215, 245	11/30/2006	MW	
707	205	11/30/2006	MW	
711	3, 118, 147, 213, 216, 221	11/30/2006	MW	
	7			
		χ.		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
			<u> </u>

SEARCH NO (INCLUDING SEARC		)
	DATE	EXMR
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	11/30/2006	MW
EAST: USPAT; USPG-PUB; DERWENT; EPO; JPO	12/13/2006	MW
•		
· · · · · · · · · · · · · · · · · · ·		